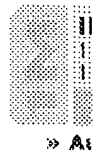


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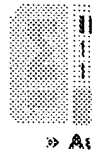
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Patent Assignment Abstract of Title

Total Assignments: 1**Application #:** 09828010 **Filing Dt:** 04/06/2001**Patent #:** NONE**Issue Dt:****PCT #:** NONE**Publication #:** US20020146150**Pub Dt:** 10/10/2002**Inventors:** David L. Patton, Gustavo R. Paz-Pujalt, John P. Spoonhower**Title:** Detecting the presence of failure(s) in existing man-made structures**Assignment: 1****Reel/Frame:** 011701/0771**Received:**
04/25/2001**Recorded:**
04/06/2001**Mailed:**
06/29/2001**Pages:**
3**Conveyance:** ASSIGNMENT OF ASSIGNORS INTEREST (SEE DOCUMENT FOR DETAILS).**Assignors:** PATTON, DAVID L.**Exec Dt:** 04/02/2001PAZ-PUJALT, GUSTAVO R.**Exec Dt:** 04/04/2001SPOONHOWER, JOHN P.**Exec Dt:** 03/29/2001**Assignee:** EASTMAN KODAK COMPANY

ROCHESTER, NEW YORK 14650

Correspondent: EASTMAN KODAK COMPANY

THOMAS H. CLOSE

PATENT LEGAL STAFF

ROCHESTER, NY 14650-2201

Search Results as of: 12/9/2004 11:34:37 A.M.

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Web interface last modified: Oct. 5, 2002

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	"5774568".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:17
L4	25	(detect\$5 inspect\$5) with (defect\$2 fault\$3 crack\$3) with image with dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 17:41
L6	87	(detect\$5 inspect\$5) same (defect\$2 fault\$3 crack\$3) same image same dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 17:42
L7	665	(detect\$5 inspect\$5) same (defect\$2 fault\$3 crack\$3) same image and dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 17:42
L8	420	(detect\$5 inspect\$5) with (defect\$2 fault\$3 crack\$3) same image and dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 17:42
L9	236	(detect\$5 inspect\$5) with (defect\$2 fault\$3 crack\$3) with image and dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:28
L14	3581	(inspect\$5) and (defect\$2 fault\$3 crack\$3) and image and dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:29
L15	2841	(inspect\$5) and (defect\$2) and image and dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:29
L16	591	(inspect\$5) and (defect\$2) and image with dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:29
L17	54	(inspect\$5) and (defect\$2) with image with dye	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:29
L18	22	17 and (radiat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 18:30

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S39	5	382/103.ccls. and ((detect\$5) near4 (material featur\$3 character\$6) near4 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:01
S40	1	"6615648".pn.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:49
S60	624	((detect\$5) near4 (material featur\$3 character\$6) near4 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:07
S61	1529	((detect\$5 sens\$4 measur\$5 inspect\$5) near4 (material featur\$3 character\$6) near4 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:50
S62	63	S61 same (separat\$6)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:03
S63	0	("6615648").URPN.	USPAT	OR	ON	2004/12/09 10:27
S64	5	("4653316" "4899296" "4958306" "5163319" "D492268").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/09 10:27
S65	3	((separat\$6) near2 (adding apply\$4) near4 (material featur\$3 character\$6) near4 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:42
S66	80	702/134.ccls.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:15
S67	78	702/8.ccls.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:49
S68	0	S66 and S61	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:49
S69	0	S67 and S61	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:49
S70	38186	((detect\$5 sens\$4 measur\$5 inspect\$5) same (material featur\$3 character\$6) same (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:50

S71	0	S66 and S70	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 10:50
S72	5	S67 and S70	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:04
S73	98	404/107.ccls.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:04
S74	2	S70 and S73	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:04
S75	320	((detect\$5 sens\$5) near3 (material\$3) near3 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:26
S76	4	S75 same ((separate\$4 individual\$4 alone) same (adding appl\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:46
S77	45	702/135.ccls.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:16
S78	0	S77 and road	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:16
S79	852	((detect\$5 sens\$5) near6 (material\$3) near6 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 13:35
S80	8	S79 same ((separate\$4 individual\$4 alone) same (adding appl\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:30
S81	33957	(dye\$1 phosphor\$2 lanthanid\$1 halide cholesteric\$2) same (radiat\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:30
S82	604	S81 same ((separate\$4 individual\$4 alone) same (adding appl\$4))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:30

S83	1	S81 same ((detect\$5 sens\$5) near6 (material\$3) near6 (ground\$4 road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:31
S84	3	S82 same (ground\$4 road\$3)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:36
S85	271	patton-david-l.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:39
S86	7	patton-david-l.in. and S81	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:36
S87	4	patton-david-l.in. and (road\$2)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:38
S88	5	patton-david-l.in. and (road\$2 man\$made)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:39
S89	71	paz-pujalt-gustavo-r.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:42
S90	9	S89 and (road\$2 man\$made)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:43
S91	1	"20030081827"	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:41
S92	83	spoonhower-john-p.in.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:42
S93	6	S92 and (road\$2 man\$made)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 11:43
S94	31	S75 same (adding appl\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 13:36

S95	1	"6535141".pn. and material\$2	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 13:10
S96	6	((detect\$5 sens\$5) near6 (defect\$2 fault\$3 crack\$3 flaw\$1 failur\$3) near6 (material\$3) near6 (road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 13:36
S97	69	((detect\$5 sens\$5) same (defect\$2 fault\$3 crack\$3 flaw\$1 failur\$3) same (material\$3) same (road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 15:26
S98	20	S97 same (adding appl\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 13:37
S99	27	S97 same (add\$6 appl\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 15:27
S10 0	127	((detect\$5 sens\$5) same (defect\$2 hole\$1 fault\$3 crack\$3 flaw\$1 failur\$3) same (material\$3) same (road\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 14:43
S10 1	35	S100 same (add\$6 appl\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 14:45
S10 2	8	S101 not S99	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 14:46
S10 3	1500	((detect\$5 sens\$5 measure\$5 inspect\$5) same (defect\$2 fault\$3 crack\$3 flaw\$1 failur\$3) same (road\$3 pavement\$2))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 15:27
S10 4	482	((detect\$5 sens\$5 measure\$5 inspect\$5) with (defect\$2 fault\$3 crack\$3 flaw\$1 failur\$3) with (road\$3 pavement\$2))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 16:08
S10 5	112	S104 same (add\$6 appl\$4)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 15:43
S10 6	9	S104 same ((add\$6 appl\$4) same (material\$2))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 15:44

S10 7	8642	((add\$5 appl\$5) near4 (road\$3 pavement\$2))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 16:09
S10 9	11301	((add\$5 appl\$5 provid\$4) near4 (road\$3 pavement\$2))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 16:09
S11 0	52	S109 same ((detect\$5 sens\$5 measure\$5 inspect\$5) with (defect\$2 fault\$3 crack\$3 flaw\$1 failur\$3))	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	ON	2004/12/09 17:38